IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Tomoyuki ISHII et al.

Appln. No.:

Group Art Unit:

Filed: HEREWITH

For: SEMICONDUCTOR MEMORY DEVICE

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to 37 C.F.R. § 1.56, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

The documents on the attached List were cited in the specification, on pages 2-3, and their relevance is indicated therein.

Respectfully submitted,

MWS:lat

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October 15, 2003

Bv:

Mitchell W. Shapiro

Reg. No. 31,568

FORM PTO-1449					Atty. Docket	No.	App:	ln. No.	
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LIST	OF	DOCUMENTS C	ITED BY A	PPLICANT					
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